

CVD Emissions - Analysis and Treatment

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Acknowledgments

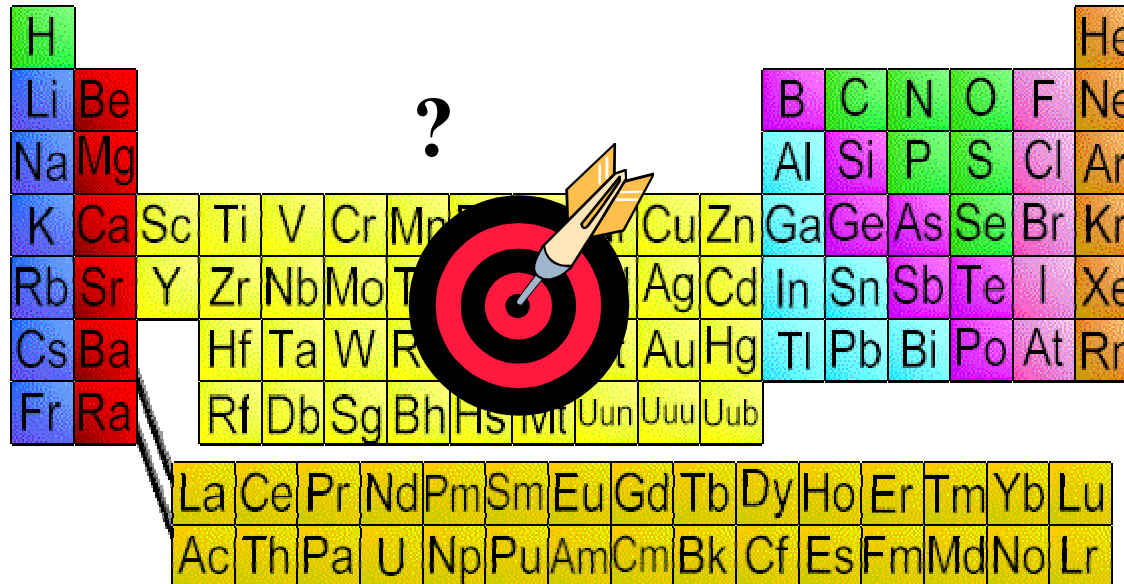
- Victor Vartanian – Motorola EPI
- Kim Reid – formerly of Motorola
- Joe VanGompel - BOCE

Overview

- CVD Trends Steering Characterization Needs
- Process Emissions Characterization
- Examples of CVD Processes Evaluated
- Point of Use Abatement
- Examples of CVD Emissions Abatement
- Conclusions

New Materials Everywhere!

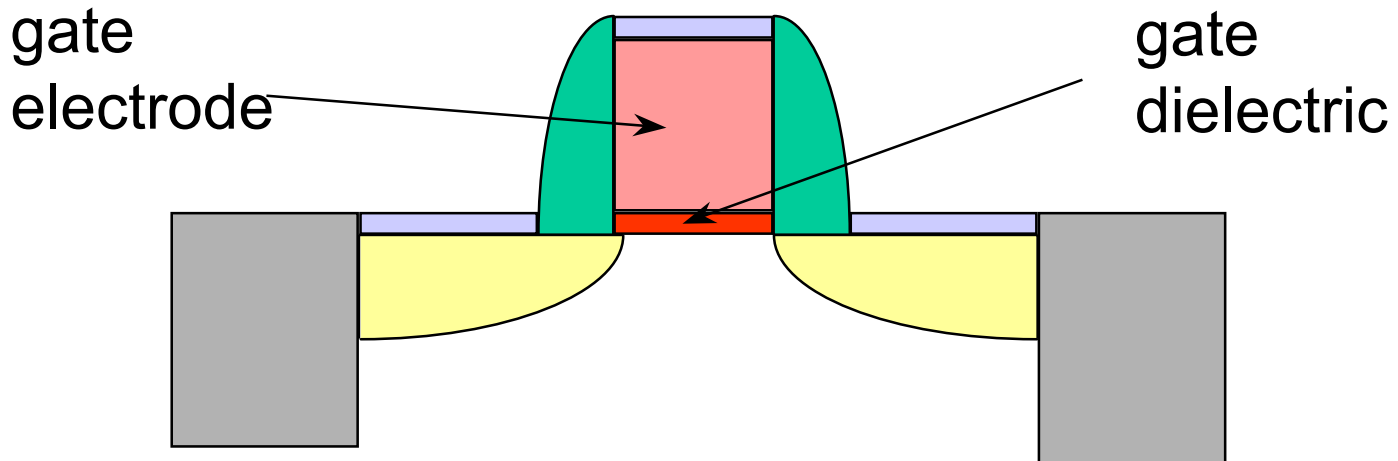
- New materials & processes are being introduced at an unprecedented rate



- Films are thinner
- Utilization should be improved

Advanced Gate Stack

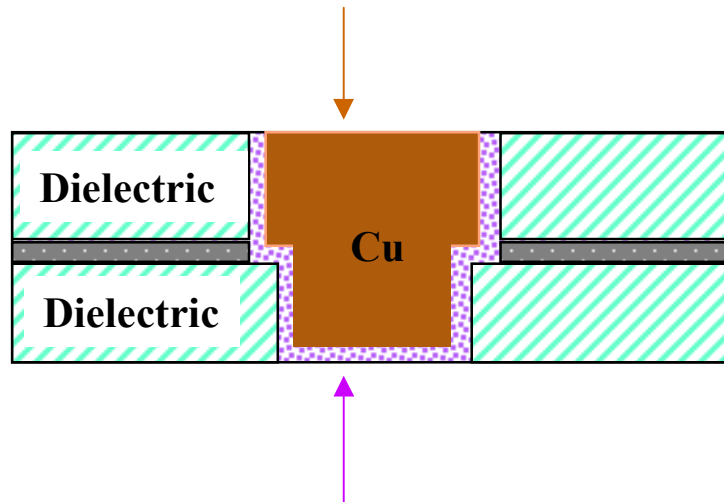
- Metal oxide gate dielectric (replaces SiO_2)
 - oxides or silicates of Ti, Ta, Sr, Zr, Hf, Al, Y, Sn, La, etc.
- Metal gate electrode (replaces doped polysilicon)
 - metals and nitrides of W, Ti, Ta, Mo, Al, Pt, etc.
- **CVD** process using metal-based precursors



Advanced Metallization

Copper Deposition

- Electroplating, **CVD**



Barrier Deposition

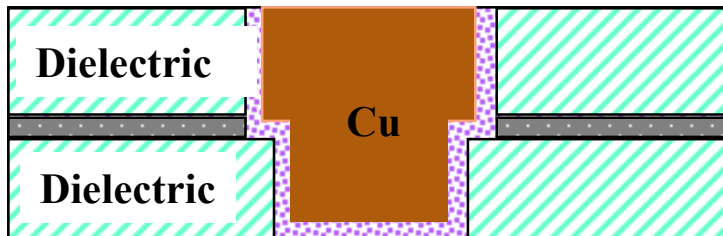
- PVD, **CVD**

- TaN, TiN, TaSiN, TiSiN, etc.

Low k Dielectrics

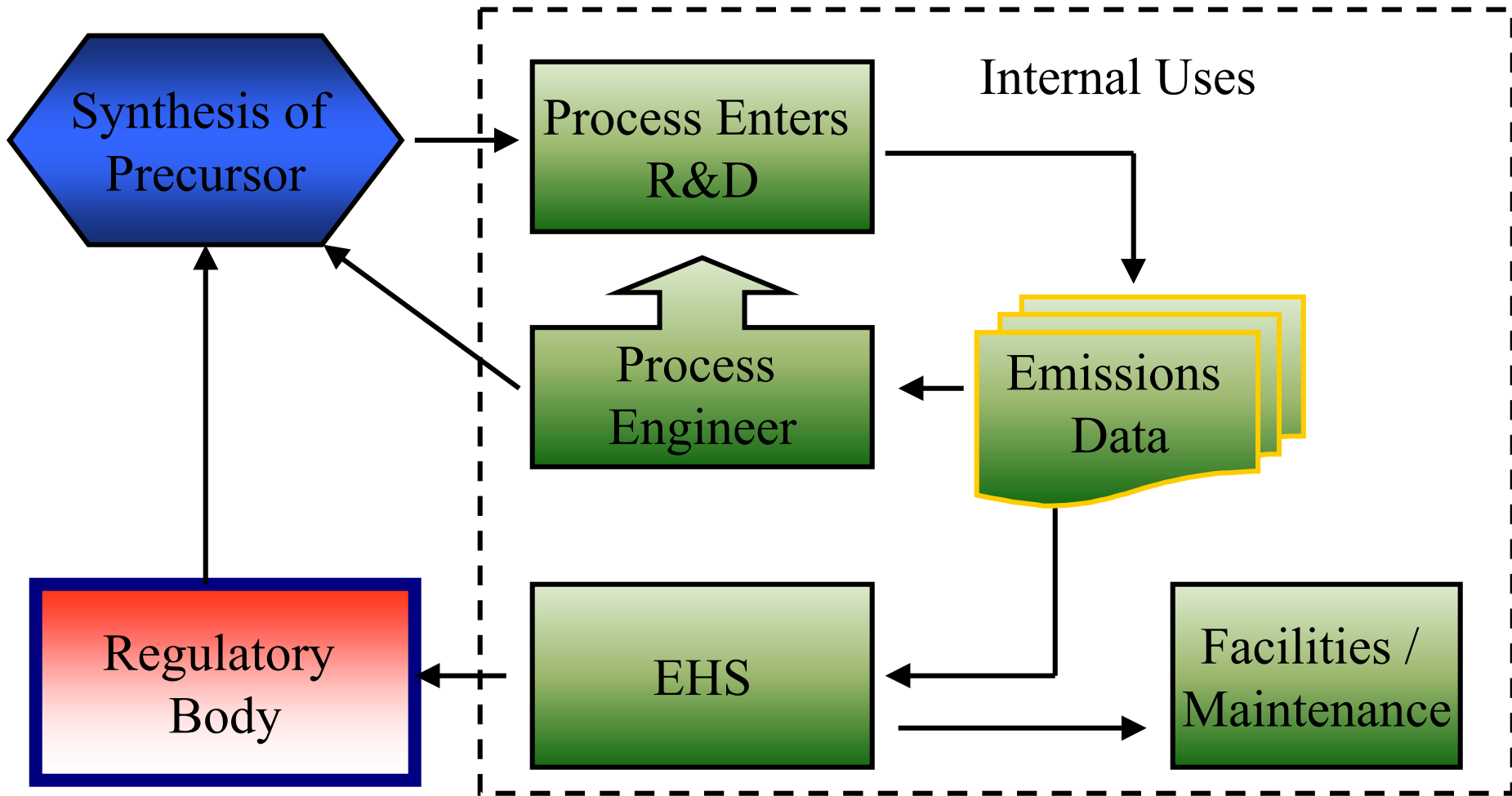
- Carbon-doped, porous organosilicates, porous polymers
- Spin-on
- **CVD**
 - organosilanes, siloxanes, halosiloxanes, silicones, etc.

$$RC = \rho \epsilon \frac{l^2}{td}$$



ρ = metal resistivity
 ϵ = dielectric permittivity
 l = line length
 t = dielectric thickness
 d = line thickness

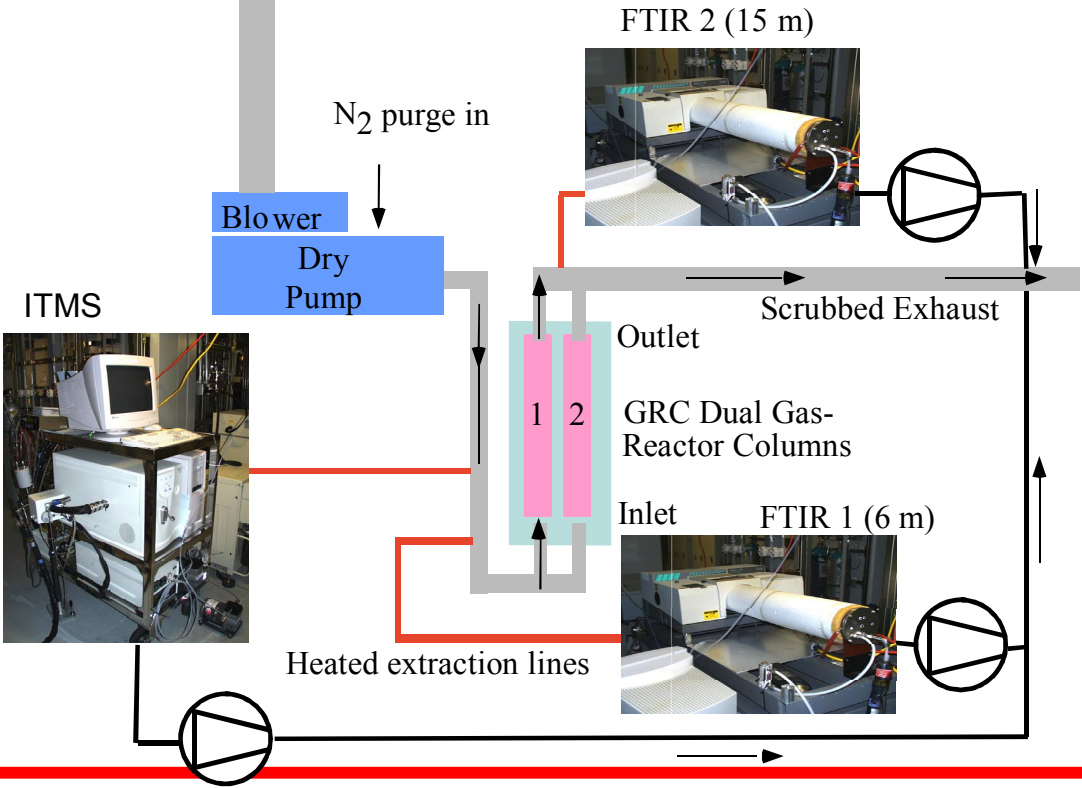
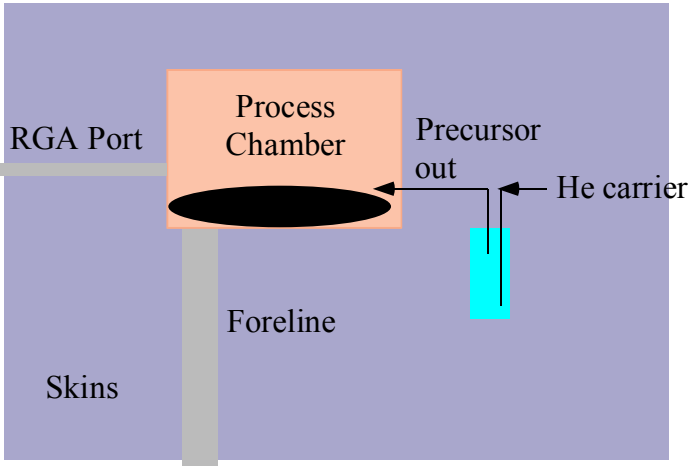
The Need for Analytical Data



Process Emissions Characterization

- Mass Spectrometry
 - Chamber monitoring, by-product identification
 - Emerging methods
 - high pressure sampling
 - trapping instruments
 - activated dissociation
- FTIR
 - Species quantification, high mass precursor identification, abatement efficiency determination
- Chemical-Specific
 - Limited in scope and availability, very sensitive

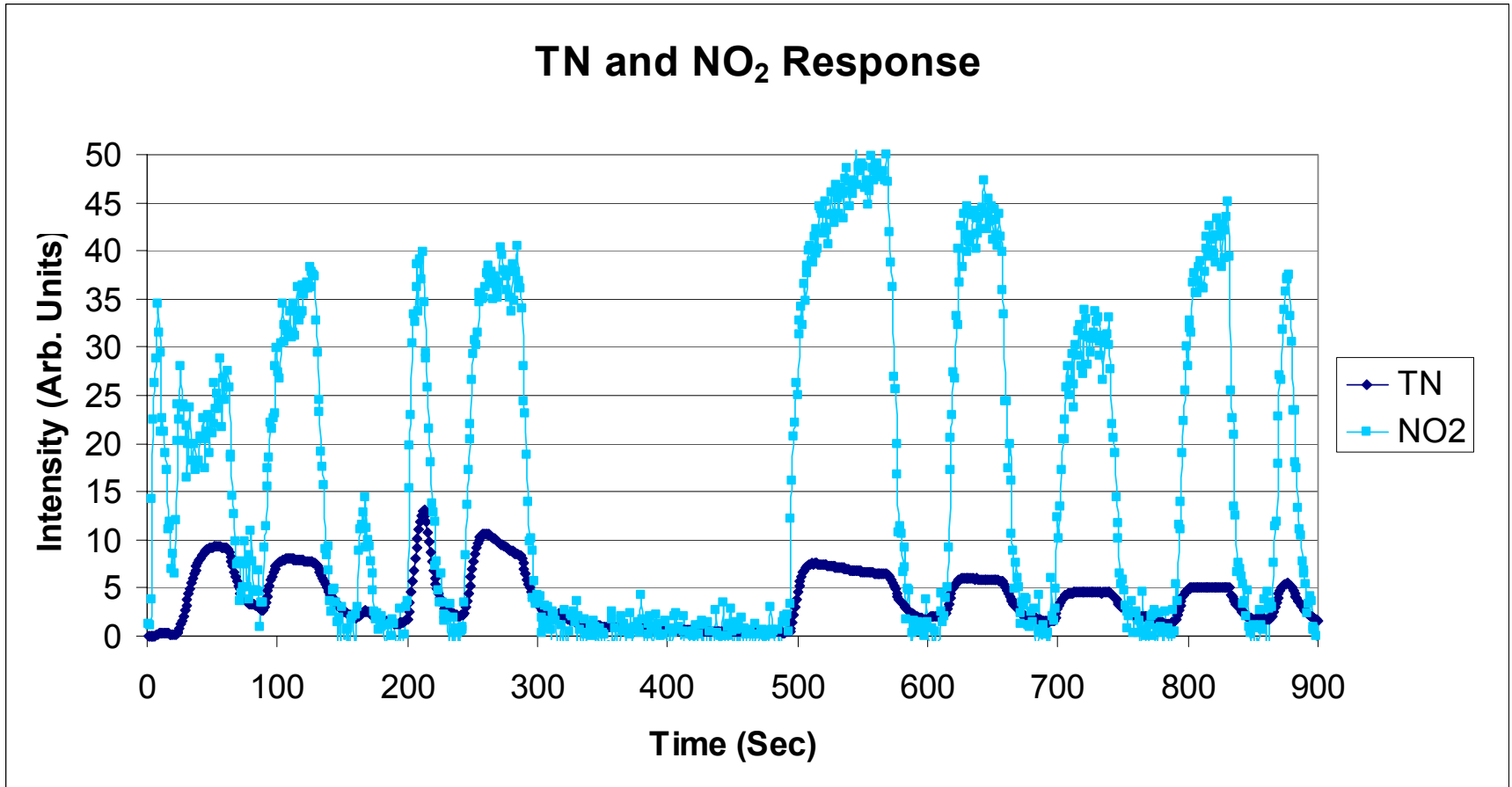
Analytical Sampling Schematic



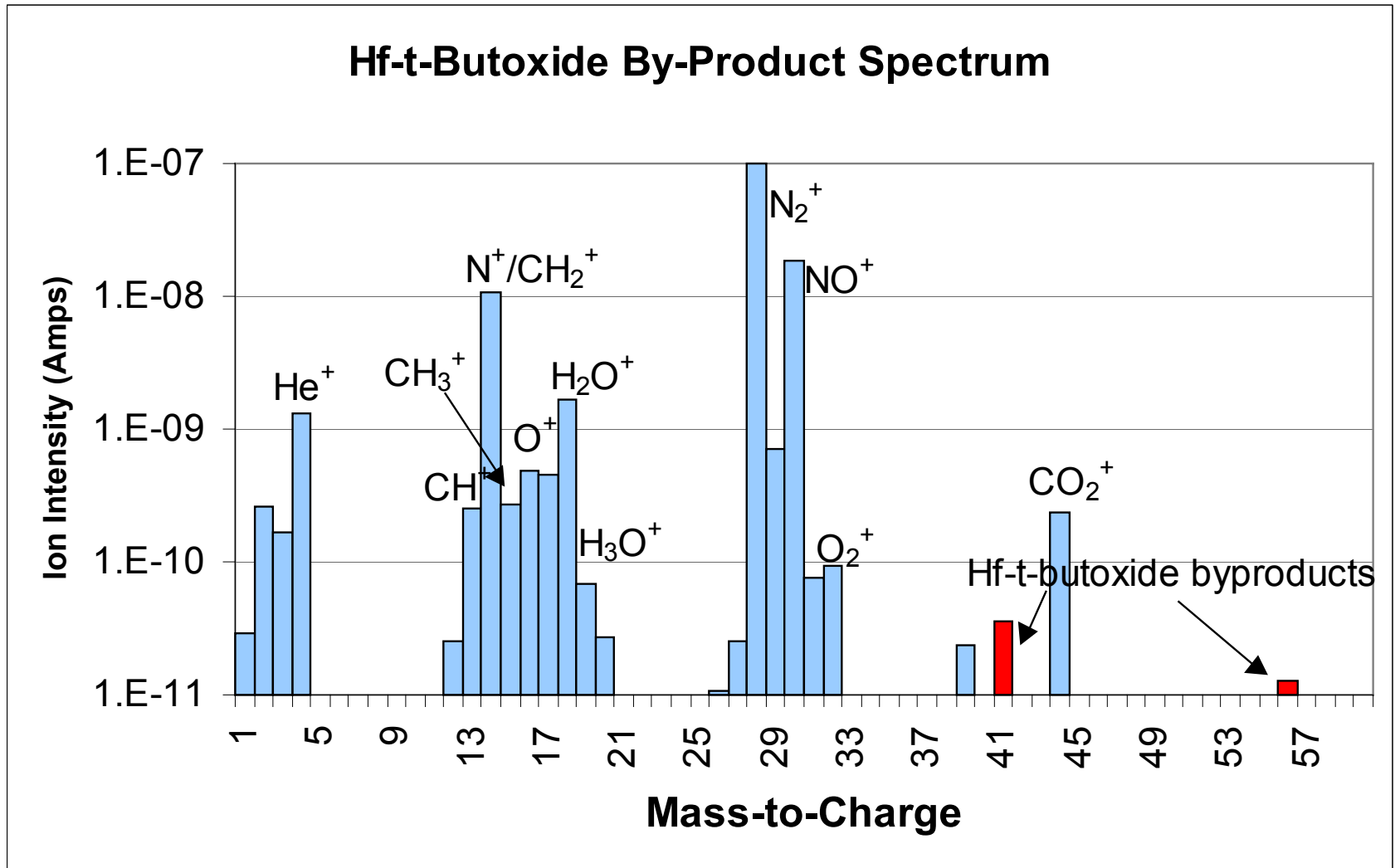
Metal-based CVD Precursors and Process By-Products Detected

- Tetranitrato titanium (TN)
 - NO, NO₂, HNO₃
- Titanium tetrachloride (TiCl₄)
 - HCl
- TDMAT
 - Dimethylamine, ammonia
- Zirconium t-butoxide
 - t-butanol, isobutylene, propylene
- Hafnium t-butoxide
 - t-butanol, isobutylene , propylene

Simultaneous Unutilized Precursor and Reaction Byproduct Monitoring for TN



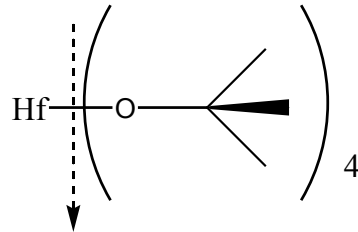
Mass Spectrum of Hf-t-Butoxide Process



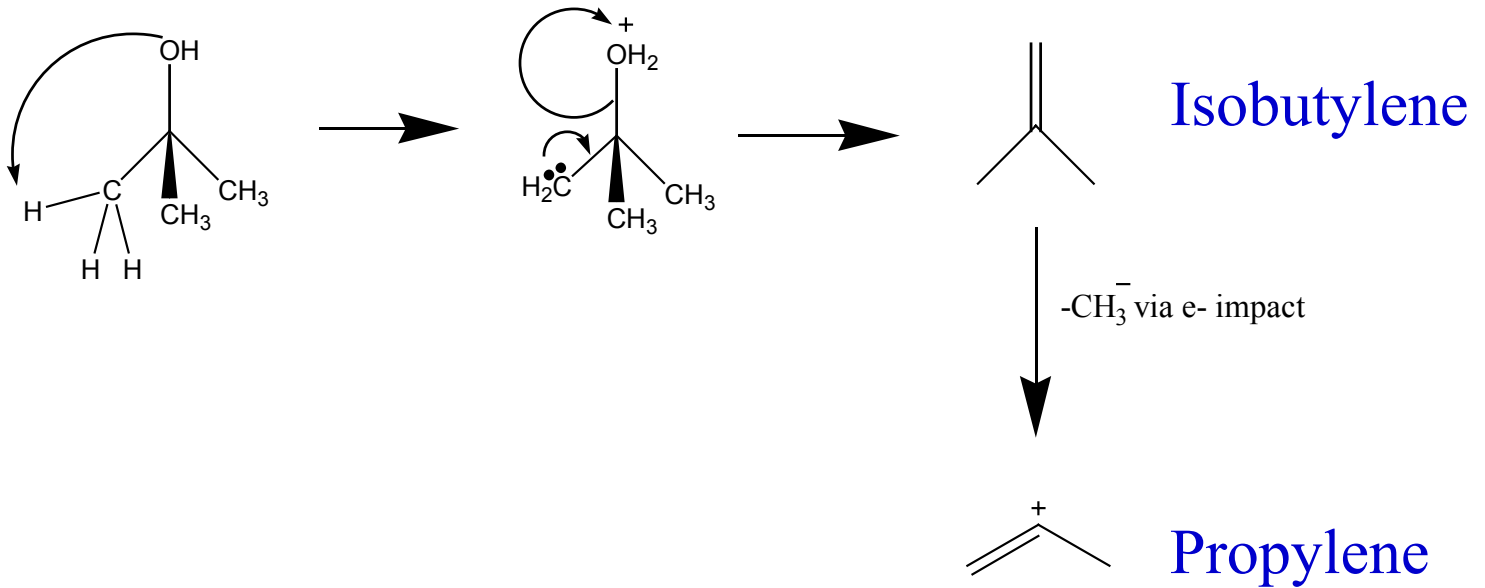
Ligand By-product Reactions

Proposed reaction for:

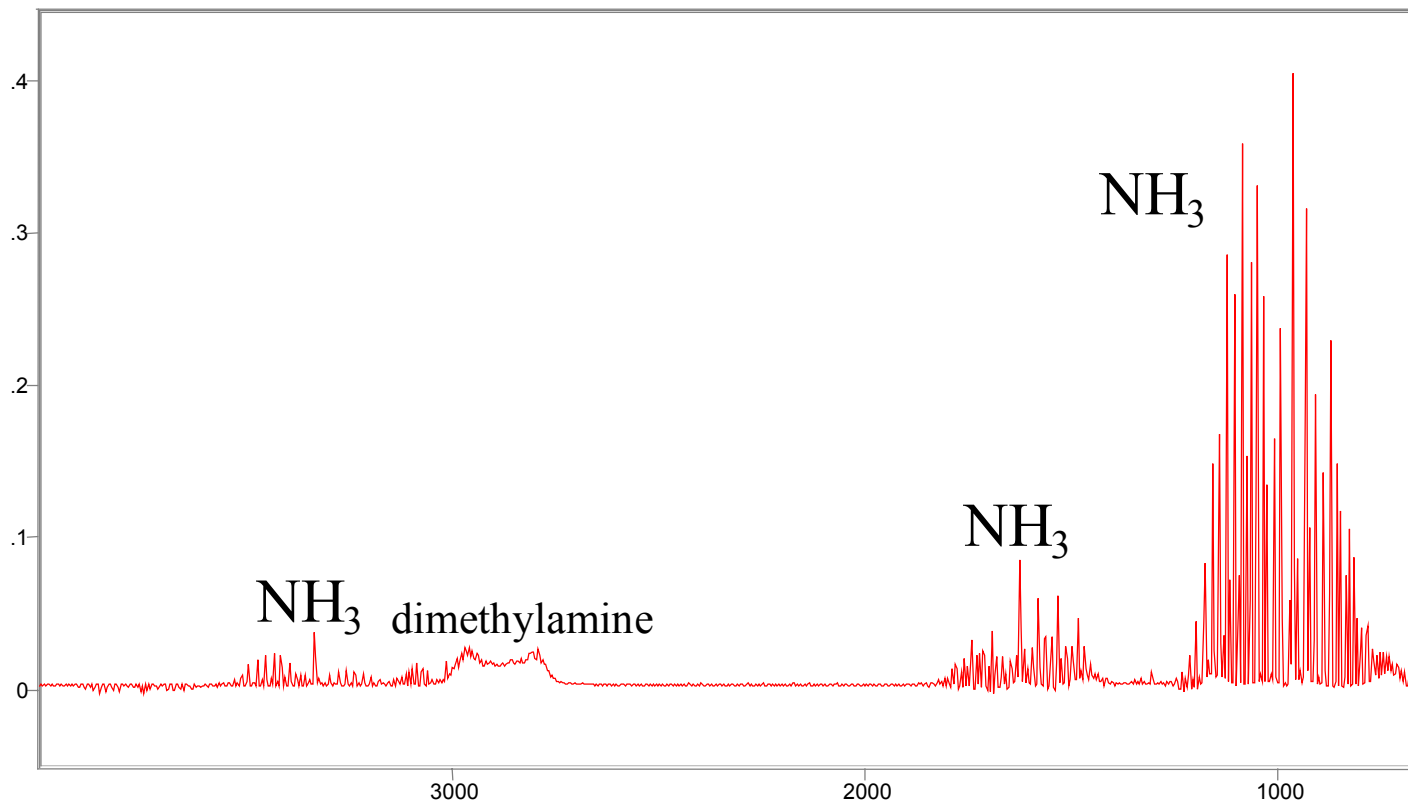
Hf-t-butoxide



Cleavage during deposition
(surface reaction)



FTIR Spectra from TDMAT Process



Absorbance / Wavenumber (cm-1)

File # 1 = TDMT0037

Thu May 03 16:26:15 2001

Y-Zoom CURSOR

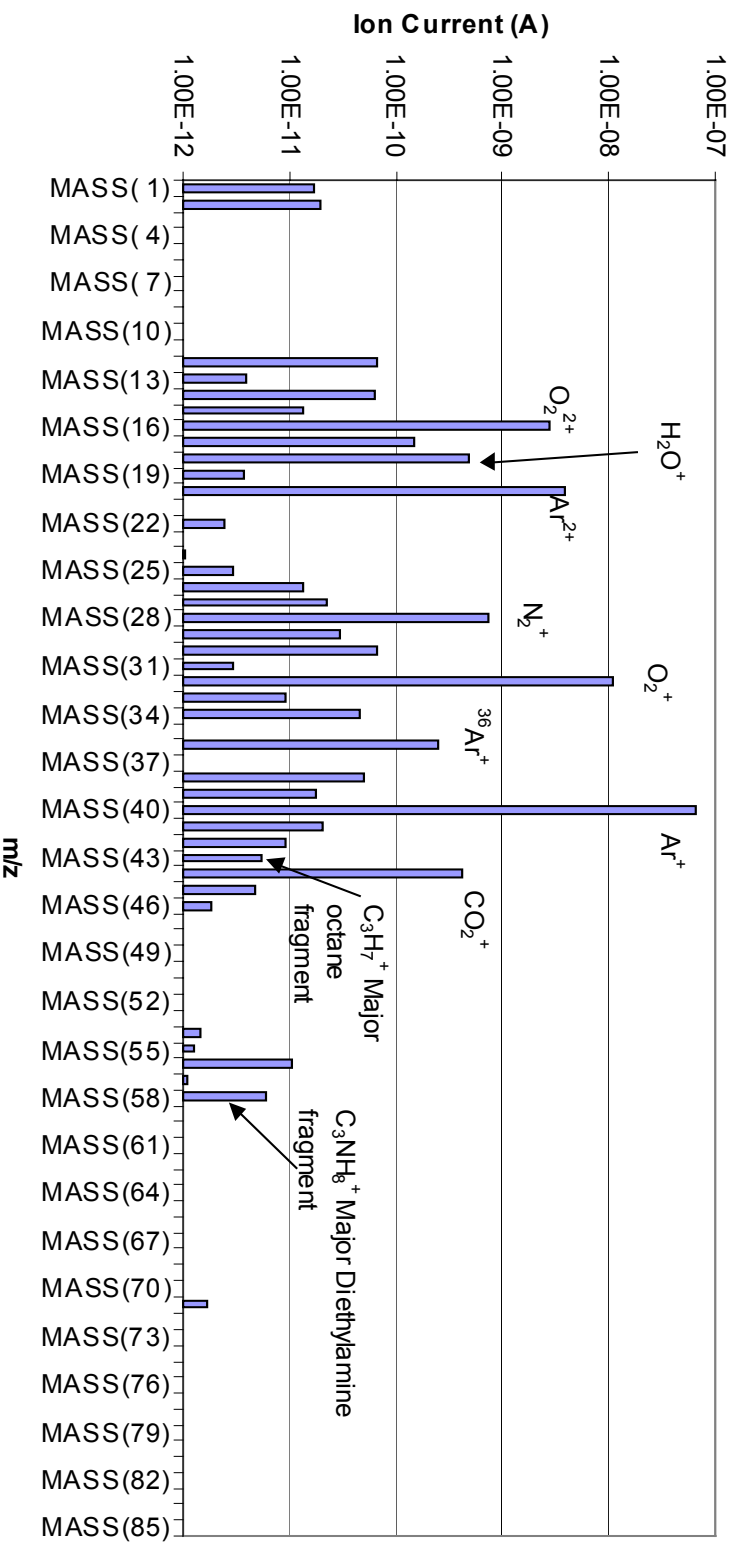
5/3/01 9:26 PM Res= .5

TDEAH

- Tetrakis diethylamino Hafnium
- Highly flammable, toxic, corrosive
- Reacts violently with water
 - forms diethylamine (toxic, extremely flammable)
- Require amine sensor (TGM) in ampoule cabinet, tool, area

Mass Spectrum from TDEAH

Mass Spectrum During TDEAH Deposition



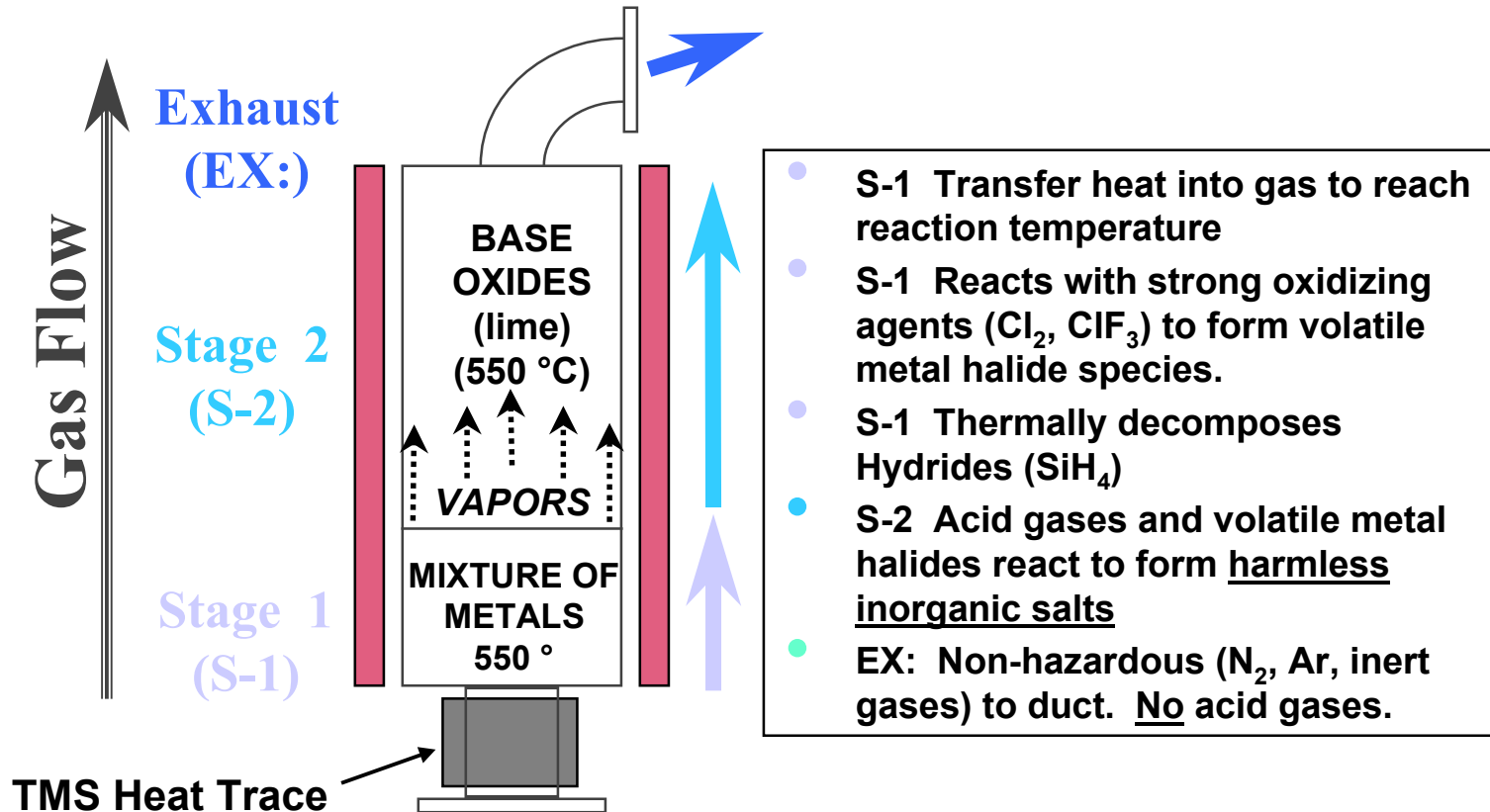
Shows diethylamine by-product

Handling Process Emissions

- Point of Use Abatement Devices
 - Minimize overall EHS impacts of precursors and by-products
 - Minimize personnel exposure during maintenance
 - Remove acid gases
 - Remove unreacted precursor to prevent deposition in exhaust ducts or release to environment

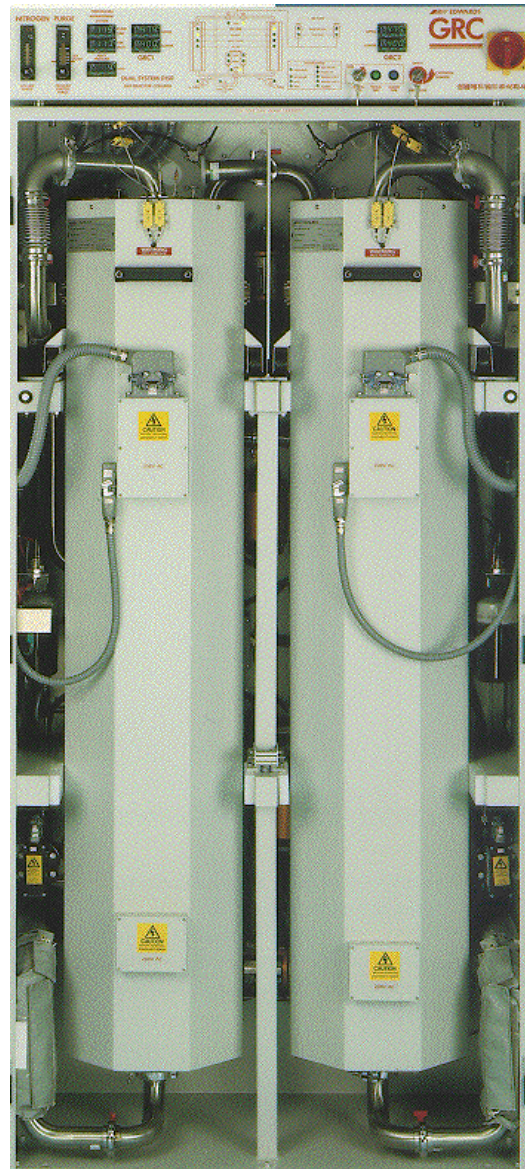
DESTRUCTION OR CONVERSION	ENTRAINMENT
-Resistive heating -Flame -Catalytic	-Chemical canister -Water scrubbing

Edwards GRC

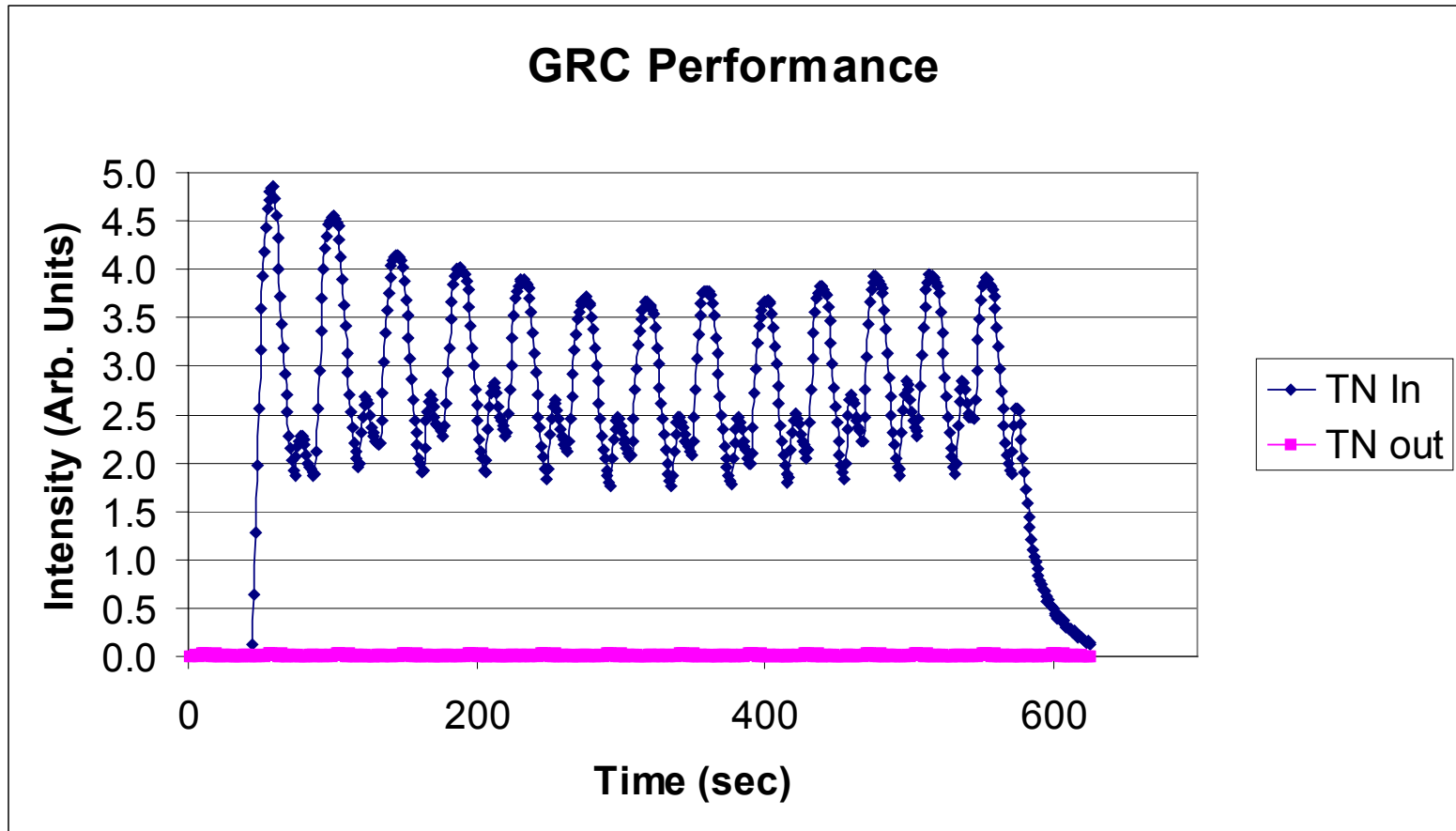


Courtesy BOC Edwards, Joe Van Gompel

D150 GRC Dual system



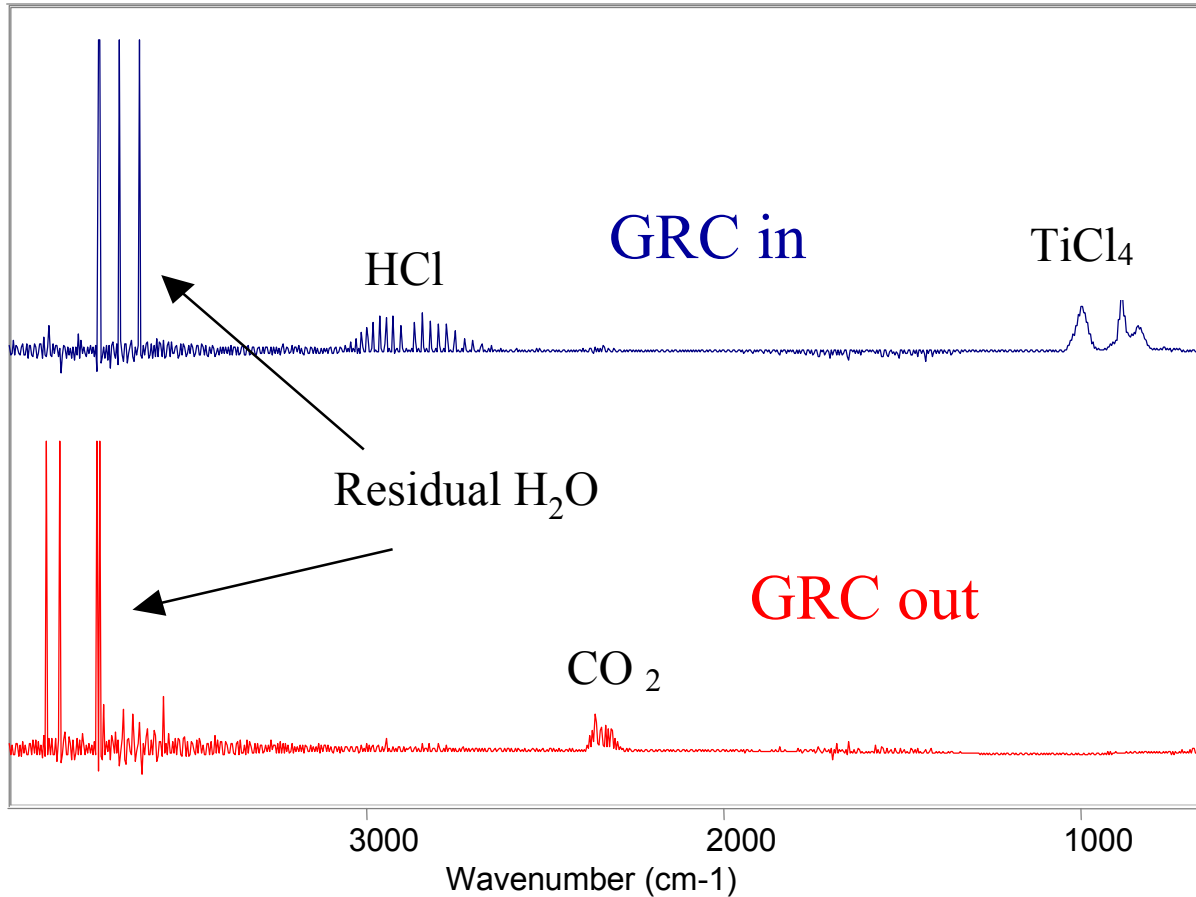
GRC Performance for TN



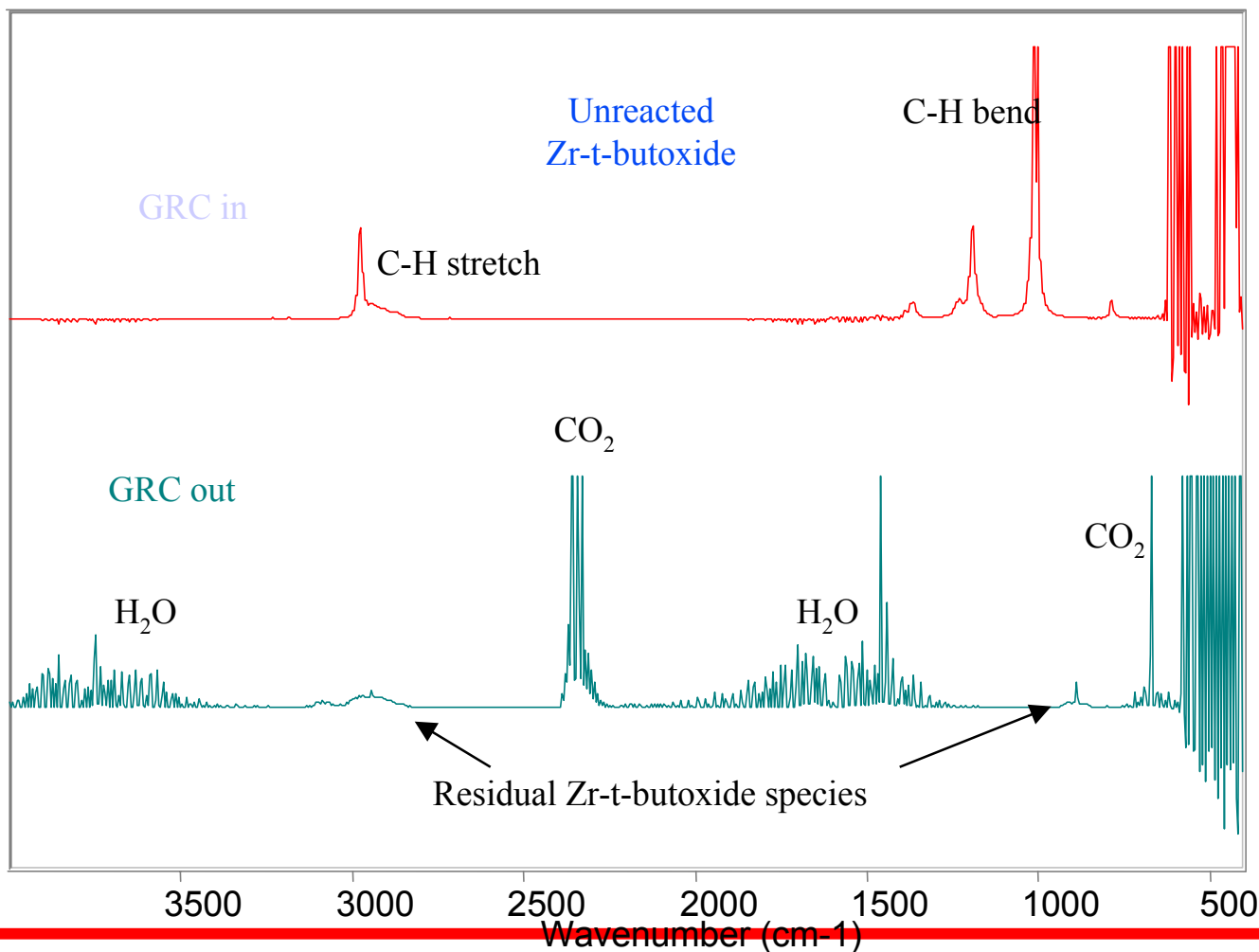
TiCl₄

- Material itself is corrosive, poisonous
- HCl is hazardous decomposition product (upon exposure to air/water)
 - monitor for HCl as TGM
- In closed CVD system, TiCl₄ and reaction by-products contained
 - HCl formed from unreacted TiCl₄ in exhaust
 - chamber maintenance becomes an issue

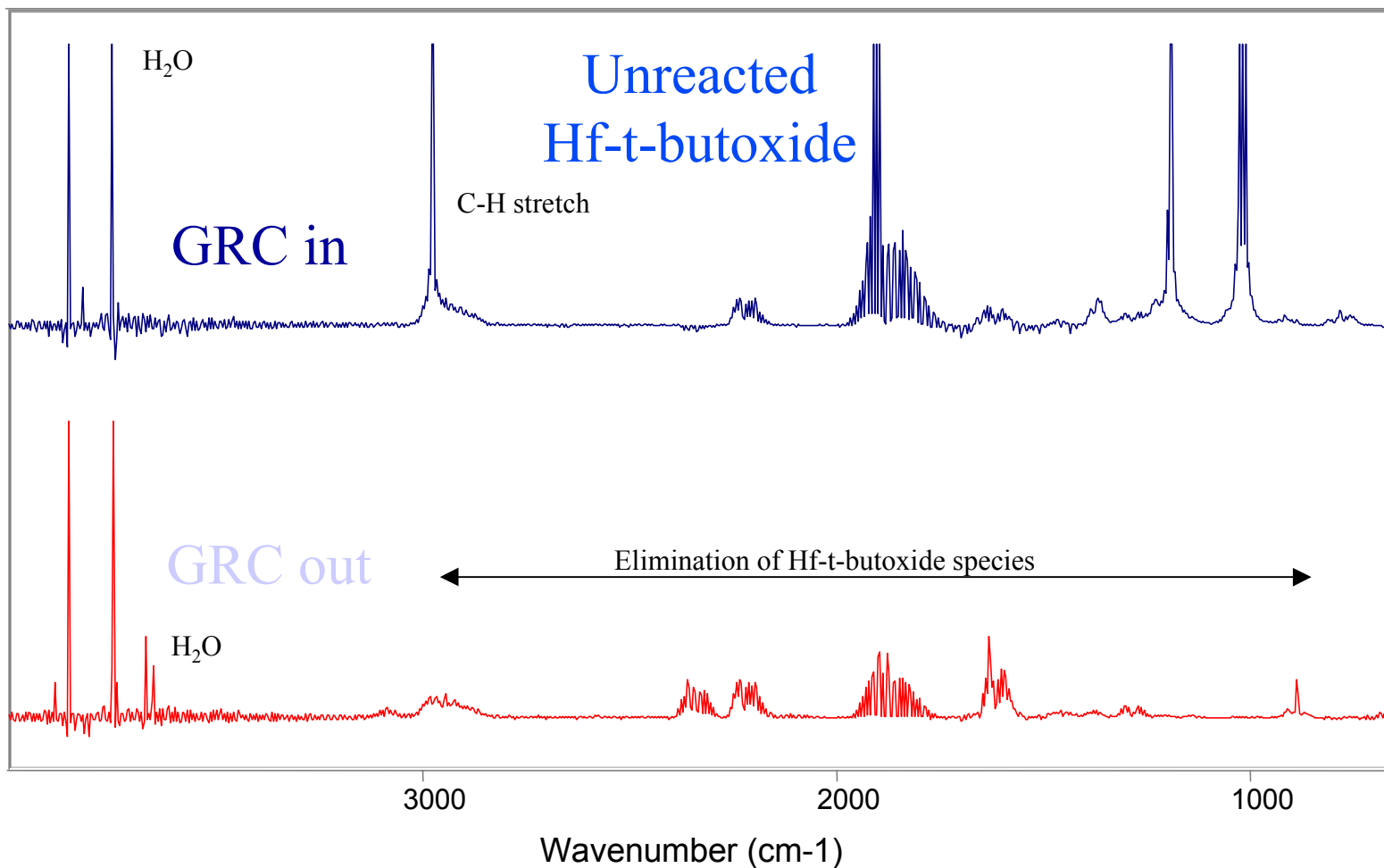
GRC Performance for TiCl_4



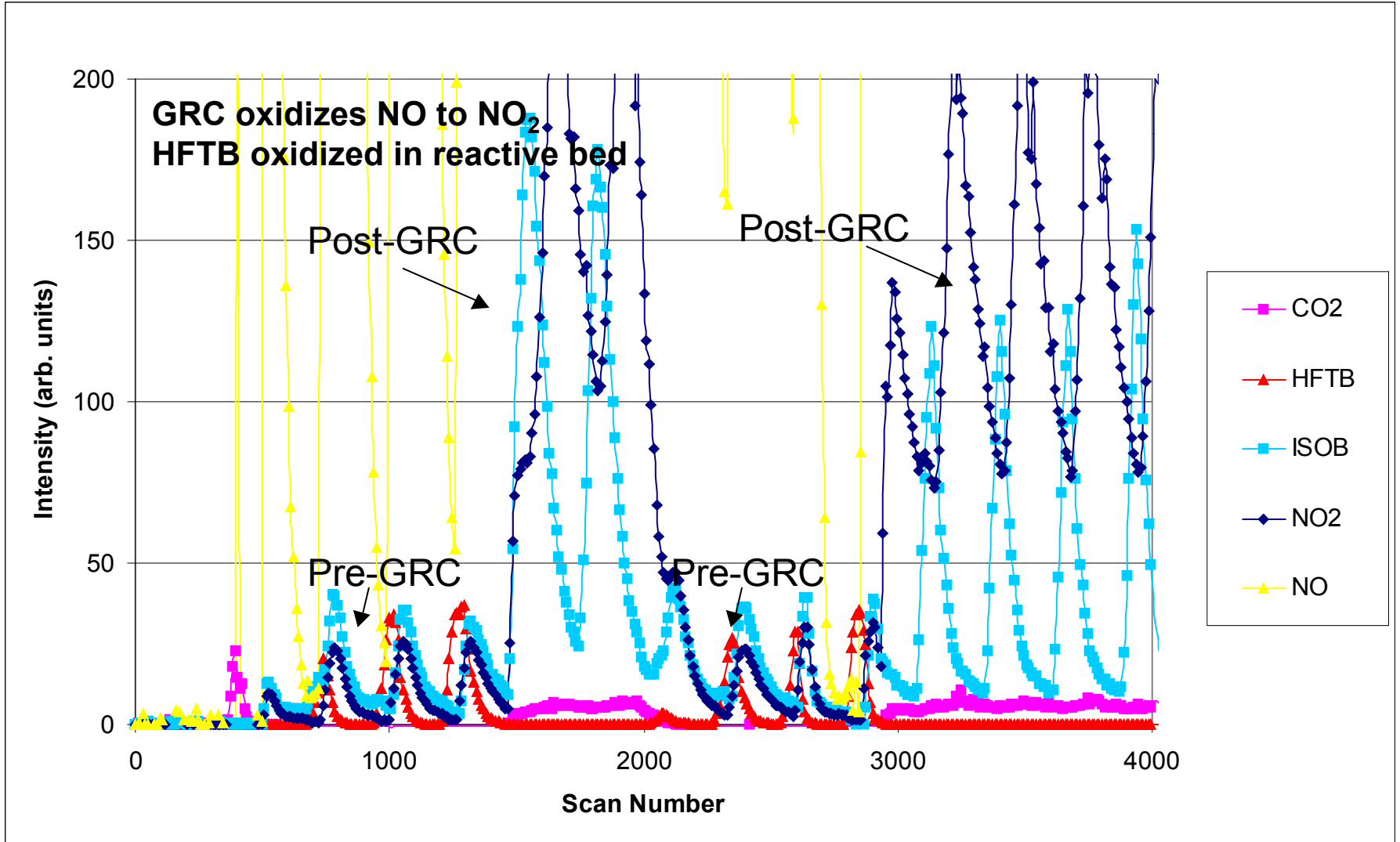
GRC Performance with Zr t-butoxide



GRC Performance for Hf t-butoxide



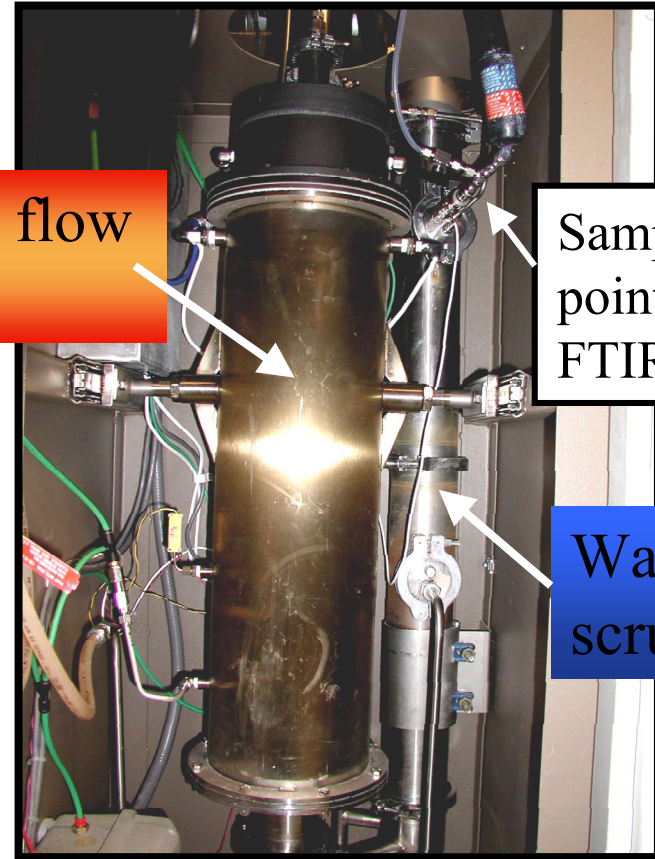
Effect of GRC on Hf-t-Butoxide



CDO



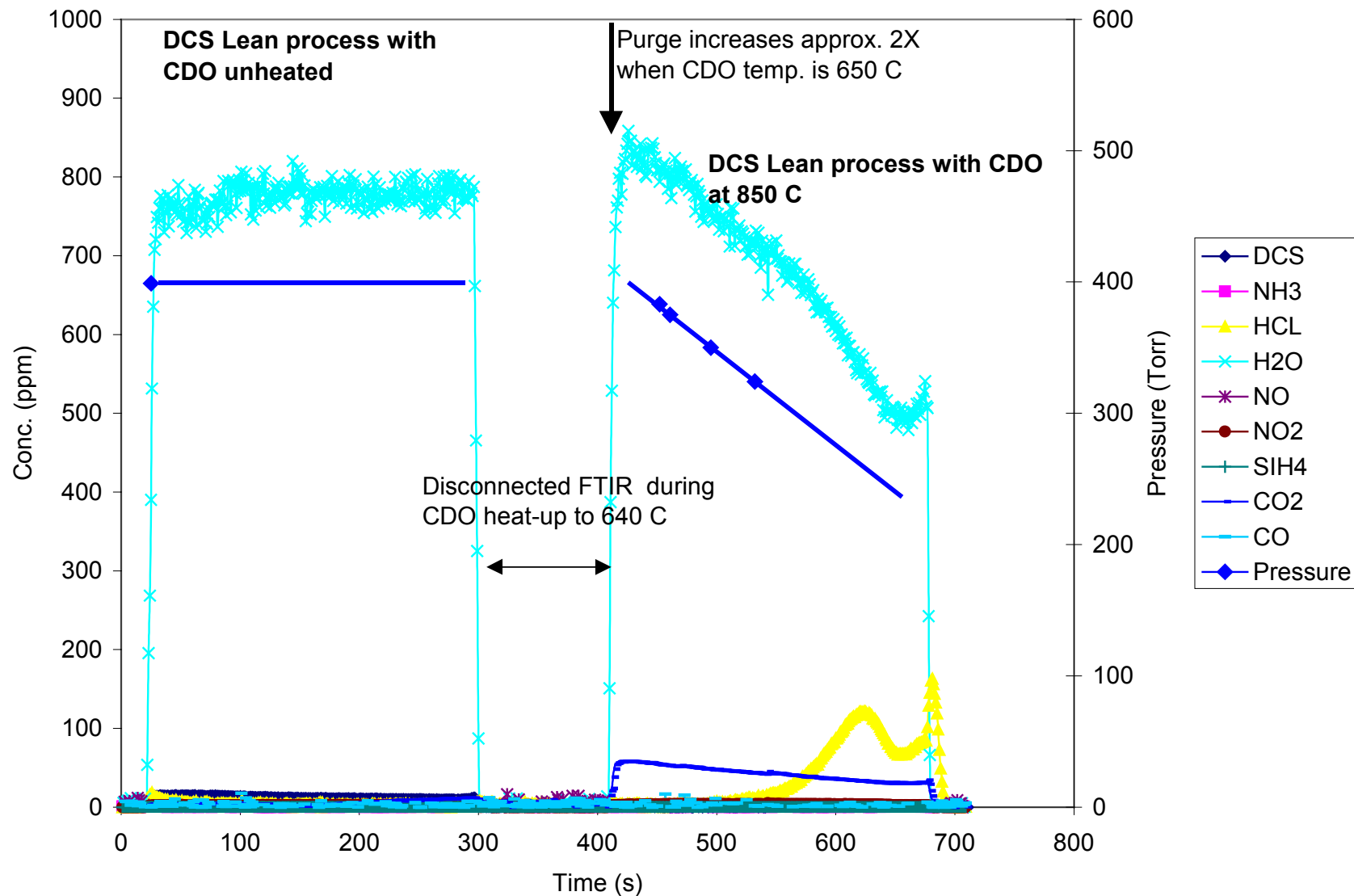
Heated flow tube



Sampling point - to FTIR

Water scrubber

Nitride Deposition - CDO Performance



Summary

- CVD emissions typically consist of unreacted precursor and ligand materials
 - determine process efficiency
 - evaluate abatement
- Collect predictive data during R&D phase
- Work with suppliers and engineers to aid design of appropriate molecules
- Abatement solution needs to fit job
- Abatement devices can be tweaked